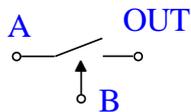


Transmission gate and Pass-Transistor Logic

- ▶ Advanced logic function or switching scheme are implemented using the feature of transistor MOS to work as a simple switch
- ▶ It has the advantage of being simple and fast. Complex gates are implemented with the minimum number of transistors (the reduced parasitic capacitance results in fast circuits)

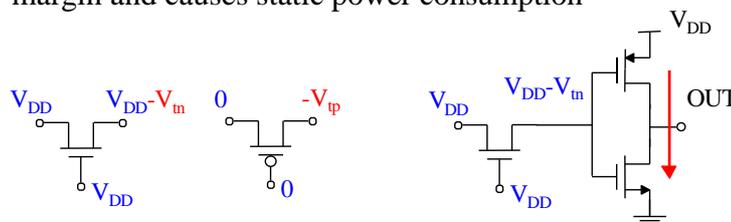


$$OUT = A \cdot B$$

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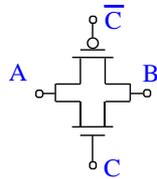
- ▶ The static and transient performance strongly depend upon the availability of a high quality switch with low parasitic resistance and capacitance
 - * A single transistor is used as switch: *Pass Transistor*
 - * N- and P-transistor are used: *Transmission Gate*
- ▶ Implementation with a single transistor reduces the noise margin and causes static power consumption



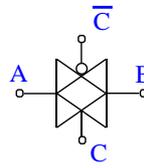
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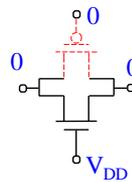
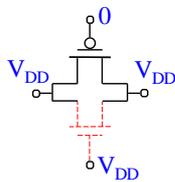
Transmission Gate



Transmission Gate Symbol

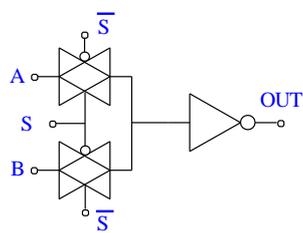


- ▶ Transmission gate has better noise margin than pass transistor



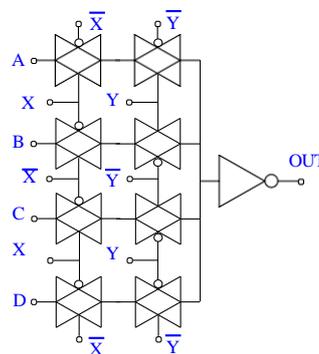
- ▶ Transmission gate is very efficient to implement some complex gate (MUX, DEMUX and XOR)

2-input Multiplexer



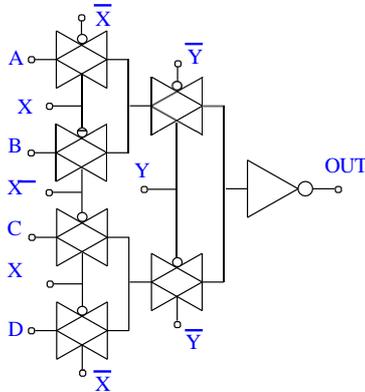
$$OUT = A \cdot S + B \cdot \bar{S}$$

4-input Multiplexer



$$OUT = A \cdot X \cdot Y + B \cdot \bar{X} \cdot Y + C \cdot X \cdot \bar{Y} + D \cdot \bar{X} \cdot \bar{Y}$$

4-input MUX as cascade of 2-input MUX

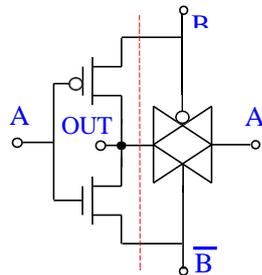


$$OUT = A \cdot X \cdot Y + B \cdot \bar{X} \cdot Y + C \cdot X \cdot \bar{Y} + D \cdot \bar{X} \cdot \bar{Y}$$

- ▶ More parasitic capacitances on internal nodes, less on the output node

2-input XOR

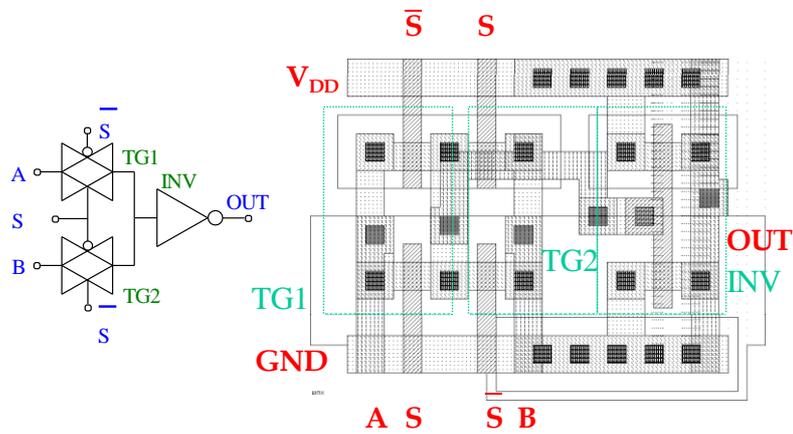
- ▶ Can be implemented with a 2-input MUX, or:



$$OUT = A \cdot \bar{B} + \bar{A} \cdot B$$

- ▶ Only the left side can implement the XOR logic function, but a threshold voltages is lost at the output without implementing the right side circuit

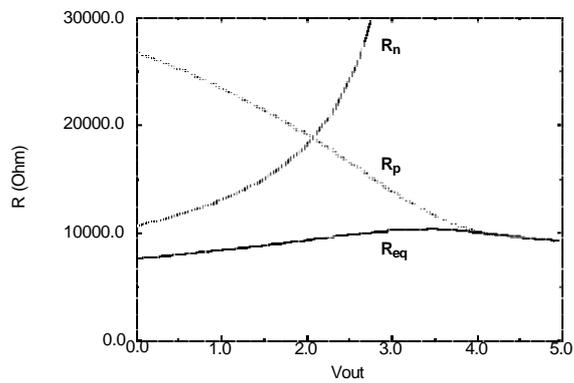
Transmission Gate MUX Layout



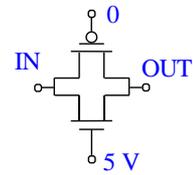
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Transmission Gate Resistance



$$\frac{(W/L)_p}{(W/L)_n} = 1.8/1.2$$



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- ▶ Despite the nonlinear behavior of the NMOS and PMOS transistors varying the input voltage, *the resistance of a transmission gate is almost constant*
- ▶ We can approximate its value with that given by the parallel of transistor resistances, assuming both in linear region

$$\frac{1}{R_{eq}} = G_{eq} = \left. \frac{dI_D}{dV_{DS}} \right|_n + \left. \frac{dI_D}{dV_{DS}} \right|_p =$$

$$= \beta_n (V_{GSn} - V_{tn} - V_{DSn}) + \beta_p (V_{SGp} + V_{tp} - V_{SDp})$$

- ▶ If the gate-source voltage is around $V_{DD}/2$, the two transistors are in linear region ($V_{DS} \approx 0$)

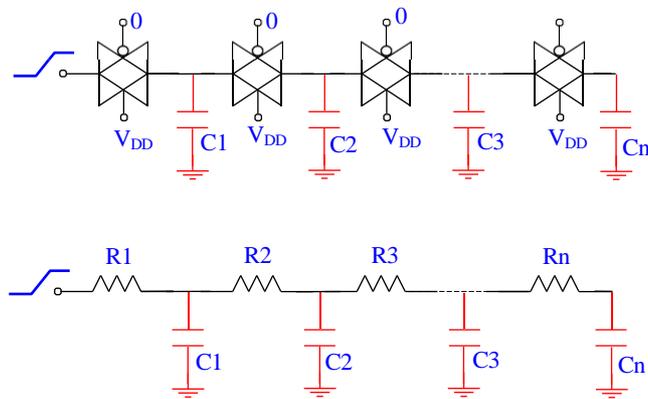
$$\frac{1}{R_{eq}} = \beta_n \left(\frac{V_{DD}}{2} - V_{tn} \right) + \beta_p \left(\frac{V_{DD}}{2} + V_{tp} \right)$$

- ▶ Assuming the threshold voltage and the gain factor of the NMOS and PMOS are equal (PMOS twice the NMOS)

$$R_{eq} = \frac{1}{n C_{ox} (W/L)_n (V_{DD} - 2V_t)}$$

- ▶ To reduce parasitic effects both transistors are generally minimum size

Transmission Gate Delay



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- ▶ Applying the *open-circuit time constant*

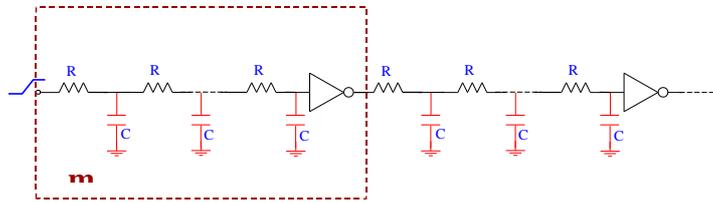
$$\tau = \sum_{i=1}^n C_i \sum_{j=1}^i R_j = RC \sum_{i=1}^n i = RC \frac{n(n+1)}{2}$$

$$R = R_{eq} \text{ and } C = 4(C_{gs} + C_{sb})$$

- ▶ Approximating the circuit with a pole-dominant behavior $\tau_{PD} = 0.69 \tau$. It increase with the square of n
- ▶ We can introduce buffer to minimize τ_{PD}

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$$\tau_{PD} = 0.69 \left[\frac{n}{m} RC \frac{m(m+1)}{2} \right] + \left(\frac{n-1}{m} \right) \tau_{PDinv}$$

$$\frac{d}{dm} \tau_{PD} = 0$$

$$0.69 RC \frac{n}{2} - \frac{n}{m^2} \tau_{PDinv} = 0$$



$$m_{opt} = \sqrt{\frac{2\tau_{PDinv}}{0.69RC}}$$

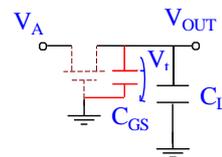
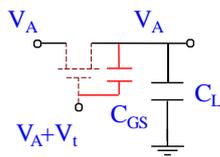
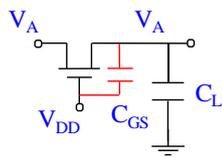
Typical value 3-4

Source of errors

► *Clock feedthrough* due to capacitive coupling

Transistor ON

Transistor OFF



Charge conservation yields

$$(C_L + C_{GS})V_{OUT} = C_L V_A - C_{GS} V_t$$

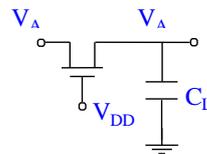
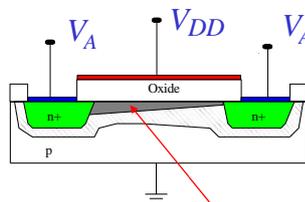


$$\Delta V_{OUT1} = V_{OUT} - V_A = - \frac{C_{GS}}{C_L + C_{GS}} (V_A + V_t)$$

Reduce with the reduction of C_{GS}

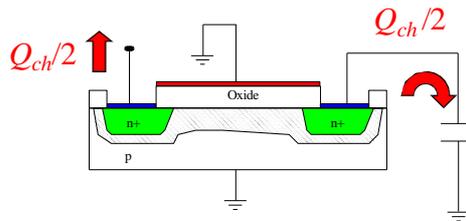
► *Charge Injection* due to redistribution of the charge in the channel

Transistor ON (triode region)



$$Q_{ch} = C_{ox} W L (V_{DD} - V_A - V_t)$$

When the transistor switch off the charge in the channel is lost. If the clock edge are sufficiently steep the charge distribute equally on the two diffusion node



$$\Delta V_{OUT2} = -\frac{1}{2} \frac{C_{ox}WL(V_{DD} - V_A - V_t)}{C_L}$$

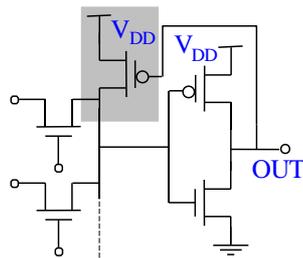
▶ *Clock feedthrough* and *Charge Injection* are lower reducing the transistor dimensions (i.e., W and L)

▶ Both the errors are reduced in Transfer Gates if the transistor are of equal dimensions.

- * the charge in the channel of equal NMOS and PMOS transistors are equal but with opposite sign
- * If NMOS and PMOS transistors are equal and switch off symmetrically the charge in the C_{GS} are equal but opposite

NMOS-Only TG with Level Restorer

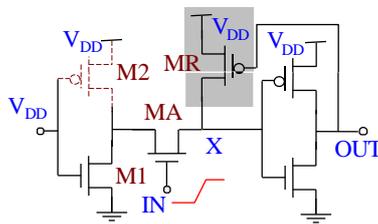
- ▶ Noise margin reduction of a pass transistor is avoided with a PMOS transistor in positive feedback which restores the output value from $V_{DD} - V_t$ to V_{DD}



- ▶ Only a PMOS transistor is needed for a set of TG which have a common output node
- ▶ *Clock feedthrough* and *Charge Injection* are higher than than in complementary TG
- ▶ Reduce the static power consumption of the next inverter but introduce a contribute due to itself
- ▶ Design strategy is close to that of ratioed logic

Design of an NMOS-Only TG

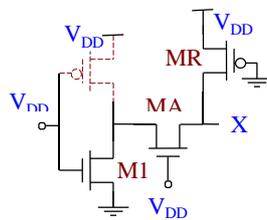
- ▶ The critical case is when the inner node was previously restored to V_{DD} (output voltage equal to 0), the first inverter has the input to V_{DD} and MR goes from 0 to V_{DD}
- ▶ During the transient a direct path between the power supply and ground exists



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- ▶ To change the output state node X must be lower than the inverter threshold voltage $V_{DD}/2$ (the positive feedback complete the inverter commutation)
- ▶ To guarantee the above condition consider the Pseudo NMOS gate M1-MA-MR



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Transistor PMOS is in triode region

$$\frac{W_n}{L_{M1}+L_{MA}} = \frac{[(V_{DD}+V_{tp})-(V_{DD}-V_{OL})](V_{DD}-V_{OL})\mu_p}{(W/L)_{MR} [2(V_{DD}-V_{tn})-V_{OL}]V_{OL} \mu_n}$$

$$\frac{W_n}{L_{M1}+L_{MA}} = \frac{\mu_p}{(W/L)_{MR} \mu_n}$$

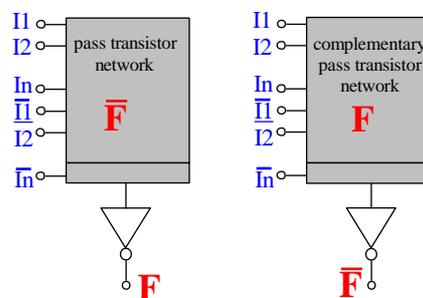
► If M1-MA are minimum size transistors

$$\left(\frac{W}{L}\right)_{MR} \leq \frac{W_{min}}{L_{min}}$$

CPL

(Complementary Pass-Transistor Logic)

► The logic is differential since two complementary data path are implemented



- ▶ Although differential signal requires extra circuitry, the differential style results advantageous in term of transistor number to implement some complex gates such as adders
- ▶ The availability of both polarity of every signal eliminates the need for extra inverter (addition speed up).
- ▶ The design is very modular. All gates use exactly the same topology, only the input are permutated. Complex gates are implemented with cascade of standard modules

- ▶ NMOS transistors with $V_m < -V_{tp}$ are needed to avoid static power consumption. (The reduced threshold improve the switching speed)

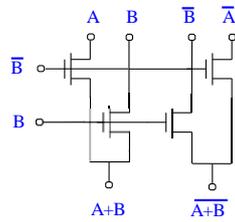
- ▶ The low V_m leads higher subthreshold current



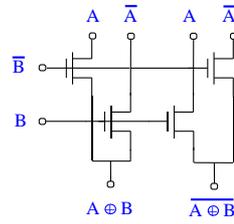
higher power supply

- ▶ The low V_m determines higher noise margin

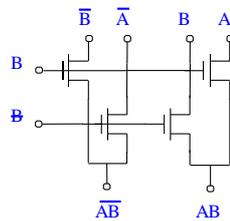
2-input OR/NOR



2-input XOR/XNOR



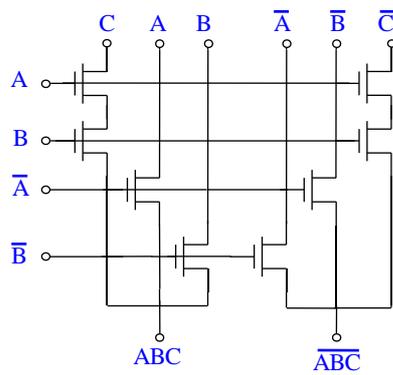
2-input AND/NAND



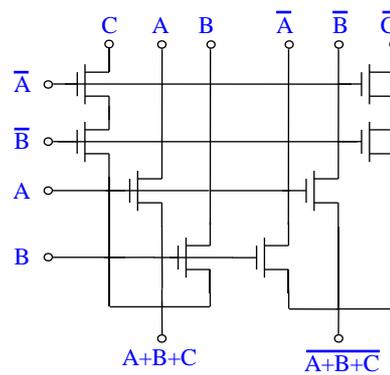
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3-input AND/NAND



3-input OR/NOR



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Layout of a 4-input NAND CPL

